Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/706,902	CHAE ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

Binh X. Tran

SEARCHED				
Class	Subclass	Date	Examiner	
216	66	3/23/2007	ВТ	
216	67	3/23/2007	ВТ	
216	71	3/23/2007	вт	
216	72	3/23/2007	ВТ	
216	74	3/23/2007	ВТ	
438	725	3/23/2007	ВТ	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
216	66	3/23/2007	ВТ	
216	67	3/23/2007	вт	
216	71	3/23/2007	вт	
216	8/72 8/74 /725	3/23/2007	ВТ	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Update search using USPAT, USPG- PUB, JPO, EPO, DERWENT, IBM_TDB databases	3/23/2007	ВТ
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